

LATS2017

18th IEEE Latin-American Test Symposium
Bogota, Colombia, 13th - 15th March 2017



CALL FOR PAPERS

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raoul.velazco@imag.fr

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yervant.zorian@synopsys.com

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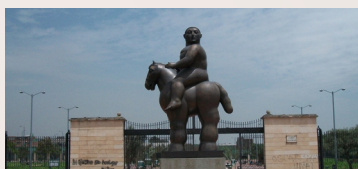
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Yervant Zorian



Gold Museum Bogota



Botero statue

CALL FOR PAPERS

The IEEE Latin-American Test Symposium (LATS, previously Latin-American Test Workshop - LATW) is a recognized forum for test and fault tolerance professionals and technologists from all over the world, in particular from Latin America, to present and discuss various aspects of system, board, and component testing and fault-tolerance with design, manufacturing and field considerations in mind. Presented papers are also published in the IEEE Xplore Digital Library. The best papers of the 18th LATS will be invited to re-submit to IEEE Design and Test of Computers, Journal of Electronic Testing: Theory and Applications - JETTA (Springer), Journal of Low Power Electronics - JOLPE (American Scientific Publishers), and IEEE Transactions on Computer-Aided Design (TCAD).

Topics of interest include but are not limited to:

- | | | |
|--|------------------------------------|------------------------------|
| - Analog Mixed Signal Test | - Economics of Test | - Radiation/EMI |
| - Automatic Test Generation | - Fault Analysis and Diagnosis | - Hardening Techniques |
| - Built-In Self-Test | - Fault Modeling and Simulation | - Software Fault-Tolerance |
| - Defect-Based Test | - Fault-Tolerance in HW/SW | - Software On-Line Testing |
| - Design and Synthesis for Testability | - Fault-Tolerant Architectures | - System-on-Chip Test |
| - Design for Electromagnetic Compatibility | - Memory Test and Repair | - Test Resource Partitioning |
| - Design for Reliable Embedded Software | - On-Line Testing | - Yield Optimization |
| - Design Verification/Validation | - Process Control and Measurements | - Hardware Security |

Paper Submission Information:

To encourage and facilitate discussions, participation will be limited. Those interested in presenting recent results at the symposium are invited to submit an extended abstract, one to three pages long, or a full length paper. PDF electronic submissions must be done via the symposium's webpage: www.lats.tttc-events.org

Authors should send papers in the IEEE format. Detailed instructions are available at the symposium's webpage. The Program Committee also welcomes proposals for panels and special topic sessions.

For additional information, please contact one of the Program Chairs:

Ernesto Sanchez – POLITO, Italy

ernesto.sanchez@polito.it

Tiago Balen - Federal University of Rio Grande do Sul, Brazil

tiago.balen@ufrgs.br

Submission Deadline (Title and Abstract): November 25th, 2016

Submission HARD DEADLINE (Full paper): December 9th, 2016

Notification of Acceptance: January 13th, 2017.

Camera Ready: January 27th, 2017.

Bogotá, Colombia's administrative and political capital, was founded in 1538 in the Bogotá savanna at 2.600 m of altitude. The city counts with the larger number of universities and research centers in the country; a rich set of museums such as the Gold Museum including more than 30.000 pieces of tumbaga gold, and the Botero Museum showing more than 100 artworks made by the known artist; in addition, the city offers a great variety of restaurants, pubs, discos, shopping malls and coffee shops to delight its visitors. As an important business hub to Latin America, the city is today recognized as an important and emerging business centre, and was included in the BestCities Global Alliance.

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